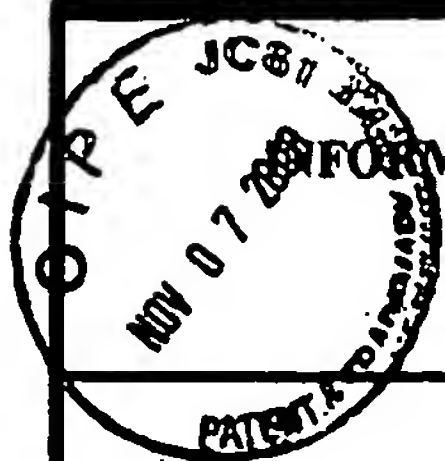


ELECTRONIC INFORMATION DISCLOSURE STATEMENT

Electronic Version v18

Stylesheet Version v18.0

Title of Invention	APPLYING PARAMETRIC TEST PATTERNS FOR HIGH PIN COUNT ASICs ON LOW PIN COUNT TESTERS						
<p>Application Number :</p> <p>Confirmation Number:</p> <p>First Named Applicant: Dennis Conti</p> <p>Attorney Docket Number: BUR920020113US1</p> <p>Art Unit: 2829</p> <p>Examiner: TANG</p> <p>Search string: (5973504 or 6192496 or 6247155 or 6348789 or 6446228 or 3922537 or 4094568 or 4884287 or 4939454 or 5000692 or 5450017 or 5754823 or 5898314 or 5909450 or 5936415 or 5952839).pn</p>							
US Patent Documents							
Note: Applicant is not required to submit a paper copy of cited US Patent Documents							
init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
Mh	1	5973504	1999-10-26	Chong	—	—	—
	2	6192496	2001-02-20	Lawrence et al.	—	—	—
	3	6247155	2001-06-12	Wright	—	—	—
	4	6348789	2002-02-19	Terao	—	—	—
	5	6446228	2002-09-03	Kobayashi	—	—	—
	6	3922537	1975-11-25	Jackson	—	—	—
	7	4094568	1978-06-13	Lee et al.	—	—	—
	8	4884287	1989-11-28	Jones et al.	—	—	—
	9	4939454	1990-07-03	Miner	—	—	—
	10	5000692	1991-03-19	Taniguchi et al.	—	—	—
	11	5450017	1995-09-12	Swart	—	—	—
	12	5754823	1998-05-19	Mudryk, Jr. et al.	—	—	—
	13	5898314	1999-04-27	Swart	—	—	—
	14	5909450	1999-06-01	Wright	—	—	—
	15	5936415	1999-08-10	Fredrickson	—	—	—
Mh	16	5952839	1999-09-14	Fredrickson	—	—	—
Signature							
Examiner Name				Date			
Mh Tang				7/06/04			



INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

Docket Number (Optional)

BUR920020113US1

Application Number

10/604230

Applicant(s)

Conti et al.

Filing Date

07/02/03

Group Art Unit

2829

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
ms		GB2342722A	2000/04/19	United Kingdom	—	—	✓	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

ms		'Special Test Chip For Testing IC Tester', IBM Technical Disclosure Bulletin, Vol. 28, No. 1, June 1985, pp. 221-222
ms		'N-Way Testpoint For Complex LSI Design', IBM Technical Disclosure Bulletin, Vol. 13, No. 10, March 1972, pp. 2937-2938

EXAMINER

DATE CONSIDERED

7/06/04

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.